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L11	spin\$4 or spun or counterspin\$4 or counterspun or (counter adj spun) or (counter adj spin\$4)	1792	L11
L10	missile\$1 or rocket\$1 or projectile\$1	46	L10
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L7	l4 and (section\$1 or portion\$1).ti,ab.	150	L7
L6	l4 and l5	1	L6
L5	counterspin\$4 or counterspun or (counter adj spun) or (counter adj spin\$4)	286	L5
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L2	(spin\$4 or spun or counterspin\$4 or counterspun).ti,ab.	345001	L2
L1	(missile\$1 or rocket\$1 or projectile\$1).ti,ab.	50587	L1

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And

canard In: All Fields

And

spin In: All Fields

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And

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And

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And

canard In: All Fields

And

spun In: All Fields

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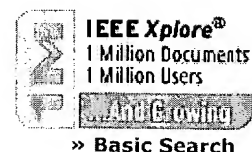
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And

canard In: All Fields

And

spun In: All Fields

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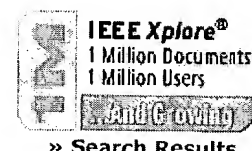
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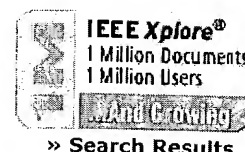
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